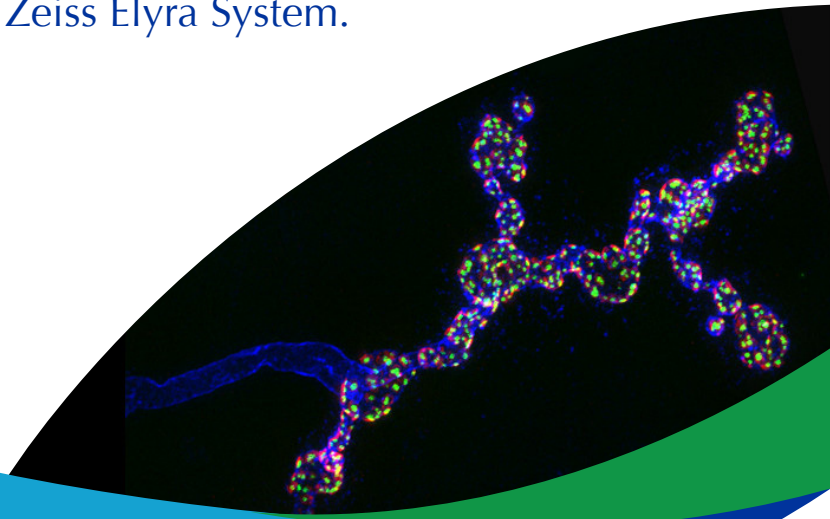


Principles of Super-Resolution Microscopy: SIM and PALM on the Zeiss Elyra System

Presented by: Bryant Chhun of Carl Zeiss Microscopy, Super Resolution Specialist
Hosted by: Analytical Imaging Facility (AIF)

Tuesday, January 29th, 10:00am- 11:00am
Forchheimer 614

Covers: The principles of SIM and PALM techniques. Specific sample prep considerations. Design features on the Zeiss Elyra System.



Albert Einstein College of Medicine
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